Vernier Caliper SERIES 532 — with fine adjustment

- Fine-adjustment aids slider positioning.
- Allows step measurement.



SPECIFICATIONS

| Metric | | ı | | | |
|-----------|---------------|------|-------|-----------|-------------------------|
| Order No. | Range (mm) | | | Depth bar | Remarks |
| 532-101 | 0 - 130 | | ±0.03 | Blade | with fine adjustment |
| 532-102 | 0 - 180 | 0.02 | ±0.03 | | |
| 532-103 | 0 - 280 | | ±0.04 | | |
| | | | | | |

| Metric/Inch | | | with metric/inch double scale | | | | | |
|-------------|-----------|----------------------|-------------------------------|----------------------------|--------------------|------------|-------------------------|--|
| | Order No. | Range | Graduation | Maximum permissible error* | | Depth bar | Remarks | |
| | Oruer No. | | | Емре | Smpe | Deptil bai | Nemarks | |
| | 532-119 | 0 - 130 mm/0 - 5 in | 0.02 mm (0.001 in) | ±0.03 mm/0.001 in | ±0.05 mm/0.0015 in | Blade | with fine adjustment | |
| | 532-120 | 0 - 180 mm/0 - 7 in | | | | | | |
| | 532-121 | 0 - 280 mm/0 - 11 in | | ±0.04 mm/0.0015 in | ±0.06 mm/0.0020 in | | | |

^{*} Partial Measuring Face Contact Error, EMPE and Shift Error, SMPE are terms (notations) used in JIS B 7507: 2016, revised based on ISO 13385-1: 2011. The measurement method is the same as before. Refer to page D-45 for details.

DIMENSIONS



